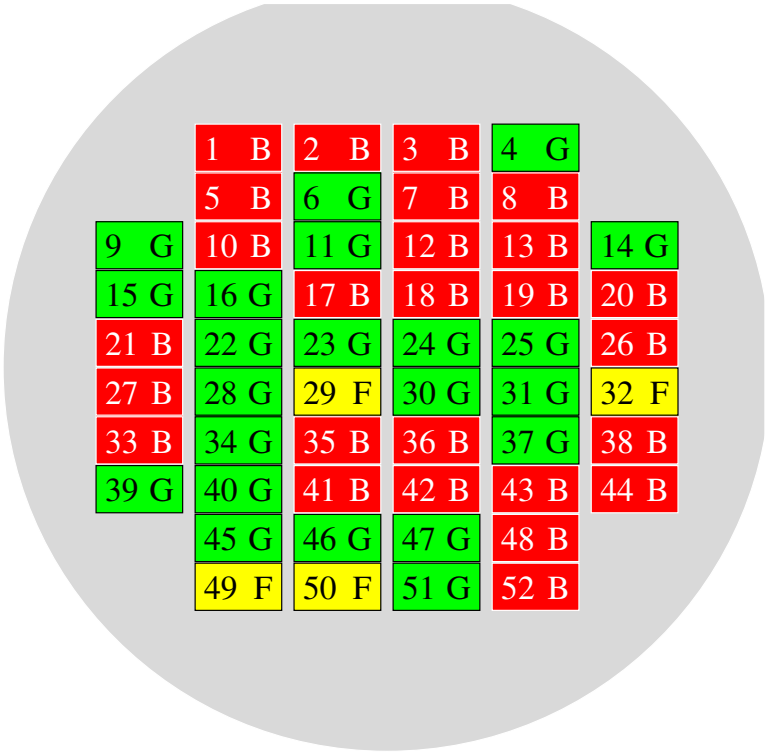
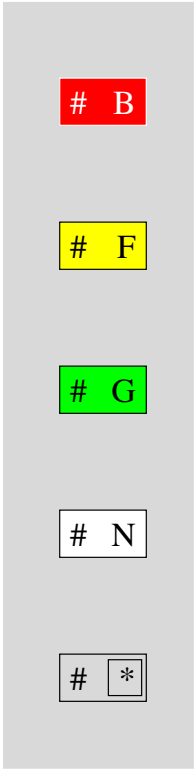
Die quality map for wafer 17 s/n: 21316-02-17

Date: 09/08/98





Bad die

Fair die

Good die

No info

Manually tagged